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Advances in In Situ Characterization of Film Growth and Interface Processes

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TABLE OF CONTENTS

In Situ Electron Microscopy as a Tool for Imaging the Growth of Nanostructures	1
<i>S. Kodambaka, F. Ross, J. Hannon, R. Tromp, M. Reuter, A. Ellis, J. Tersoff, B. Kim, E. Stach</i>	
Quantum Effects in Low Energy Electron Microscopy: A 3D View of Thin Film Growth and Structure	33
<i>M. Alman</i>	
In Situ Scanning Electron Microscopy of Single-Walled Carbon Nanotube Growth during Chemical Vapor Deposition	59
<i>Y. Homma, D. Takagi, T. Chokan</i>	
High-Pressure RHEED Controlled PLD of Complex Oxides	83
<i>D. Blank</i>	
Advances in the Use of RHEED-TRAX and Cathodoluminescence for In-Situ Growth Characterization and Control	130
<i>K. Lee, R. Thompkins, S. Chandril, C. Keenan, E. Schires, D. Lederman, T. Myers</i>	
Quantitative Study of Sub-Monolayer Growth of Ge(001) Homoepitaxy using Reflection High Energy Electron Diffraction	159
<i>B. Shin, M. Aziz</i>	
In Situ RHEED Monitoring of Epitaxial Film Growth on Continuously Moving Tape	173
<i>V. Matias, R. Steenwelle</i>	
Magnetic Interface Interactions in Cuprate - Manganite Heterostructures and Superlattices	184
<i>H. Habermeier, J. Chakhalian, G. Christiani, C. Bernhard, B. Keimer</i>	
Monitoring Oxide Thin Film Growth with In-Situ Atomic Force Microscopy	N/A
<i>J. Broekmaat, F. Roesthuis, A. Brinkman, H. Rogalla, D. Blank, G. Rijnders</i>	
In Situ Characterization of Iron Oxides Quantum Dots and Thin Film Growth Using UHV AFM	209
<i>J. Thery, M. Gordon, T. Baron, C. Dubourdieu</i>	
Optical Conductivity of Electroless Deposited Percolating Silver Films	229
<i>S. Kooij, A. de Vries, H. Wormeester, A. Mewe, B. Poelsema</i>	
In-Situ Investigation of Surface Oxygen Vacancies in Perovskites	244
<i>F. Granozio</i>	
Stress Evolution During Electrochemical Deposition of Thin Films	280
<i>T. Luo, R. Cammarata</i>	
Stress Evolution Due to Island Coalescence During Film Growth	294
<i>A. Bhandari, B. Sheldon, S. Hearne</i>	

The Electronic Structure of 1,7-PCB10H11 Molecular Films	307
<i>S. Balaz, N. Boag, N. Platt, D. Dimov, J. Brand, P. Dowben</i>	
Surface Reactions of Metal Catalysts for Carbon Nanotubes on an Oxide Thin Layer/Si Substrates Studied by In-Situ Micro X-Ray Adsorption Spectroscopy Using SPELEEM	313
<i>F. Maeda, H. Hibino, S. Suzuki, F. Guo, Y. Watanabe</i>	
Characterization of Alumina Optical Waveguides Grown by Ion Beam Assisted Deposition for SPARROW Biosensors	319
<i>P. Poloju, P. Samudrala, J. Nightingale, D. Korakakis, L. Hornak</i>	
Efficient and Broad-range Zoom Optics Beam Delivery Systems for Laser Material Processing	325
<i>D. Kirilov, C. Eom, T. Gebale, M. Branesco, C. Naudin, V. Teodorescu, G. Socol, I. Balasz, C. Ducu, J. Jaklovszky</i>	
X-Ray Standing Wave Imaging of Atoms at Interfaces	337
<i>M. Bedzyk, C. Kim, A. Kazimirov, J. Elam, S. Christensen, D. Goswami, M. Hersam, M. Pellin, P. Stair</i>	
Synchrotron-Based In Situ X-Ray Studies of Pulsed Laser Deposition	362
<i>J. Brock</i>	
Determining the Growth Mode of SrTiO₃ (001) via Pulsed Laser Deposition using In-situ X-Ray Reflectivity	463
<i>J. Ferguson, G. Arikan, A. Amassian, D. Dale, A. Woll, J. Brock</i>	
Interlayer Transport in Pulsed Laser Deposition of SrTiO₃ Studied by Time-Resolved Surface X-Ray Diffraction	478
<i>G. Eres</i>	
Quantitative Determination of Ion Impact- Induced Smoothing on Sapphire Surfaces	489
<i>H. Zhou, L. Zhou, Y. Wang, R. Headrick, A. Ozcan, Y. Wang, G. Ozaydin, K. Ludwig</i>	
In-Situ Synchrotron X-Ray Diffraction During Pulsed Laser Deposition of Complex Oxides	506
<i>G. Rijnders, A. Janssens, V. Vonk, M. Huijben, S. Harkema, D. Blank</i>	
Time-Resolved X-Ray Reflectivity Study of Interfacial Reactions and Intermetallic Formation During In-Situ Continuous Heat-Treatment of Cu/Mg/Cu Layers	522
<i>M. Gonzalez-Silveira, J. Rodriguez-Viejo, M. Clavaguera-Mora, T. Bigault</i>	
Significant Shift of Phase Transition Temperature of Strained SrRuO₃ Thin Films	539
<i>K. Choi, S. Baek, H. Jang, L. Belenky, C. Eom</i>	
In Situ Infrared Absorption Spectroscopy for Thin Film Growth by Atomic Layer Deposition	549
<i>Y. Wang, M. Dai, M. Ho, S. Rivillon, Y. Chabal</i>	
The "Silanone" Structure as the First Step of the Silicon Oxidation	569
<i>A. Hemeryck</i>	

Nano-Scale Imaging with Table-top Extreme Ultraviolet Lasers	581
<i>C. Menoni, G. Vaschenko, C. Brewer, F. Brizuela, Y. Wang, M. Larotonda, B. Luther, M. Marconi, J. Rocca, W. Chao, E. Anderson, D. Attwood, A. Vinogradov, I. Artioukov, Y. Pershyn, V. Kondratenko</i>	
In Situ Temperature Measurement; What is the Temperature of a Growing Oxide Thin Film	599
<i>G. Koster</i>	
In Situ Characterization of Gas-Phase Processes During Hafnium Oxide Atomic Layer Deposition	620
<i>J. Maslar, W. Hurst, D. Burgess Jr., W. Kimes, N. Nguyen, E. Moore</i>	
In Situ Defect Spectroscopy: Probing Dangling Bonds During a-Si:H Growth by Subgap Absorption	632
<i>R. Van de Sanden, I. Aarts, A. Pipino, E. Kessels</i>	
Author Index	